OEOSC Laser Damage Standard Development

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- Existing standards for laser damage threshold measurement may not produce accurate, repeatable measurements
- Procedure is open to interpretation and these interpretations affect the resultant measure
- ISO standard takes a one size fits all approach

One procedure for all users and applications, pulse lengths, wavelengths, damage morphology

 This talk introduces the thoughts behind a US National (OEOSC TF7) proposal for revision



Overview Of Laser Induced Damage

- Analysis germane to thin film coatings on optical substrates.
- Laser damage can occur through either intrinsic or defect driven mechanisms.
- Intrinsic damage can Include absorbative processes or multiphoton ionization.
- In most dielectrics however the onset of damage is well below the intrinsic threshold and driven by defects in the film.
- This talk Introduces the thoughts behind a US national (OEOSC TF7) proposal for revision based on a test designed to interrogate a defined area and find these defects



- Laser damage level Is driven by defects in the optical surface
- When performing a test the probability of finding a failing site is a function of the area interrogated, the defect density of the sample and the test fluence.
- Data generated is highly dependent on laser spot size and the area interrogated when the test is performed.
- Variance In area between tests and choice of test locations can lead to variance the measured damage threshold.

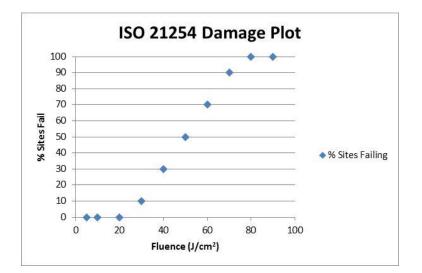


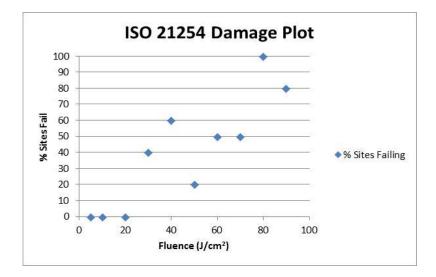
Current ISO Approach

- Test is performed under current standard by choosing laser spot size, and testing multiple locations with increasing laser fluence levels In a fixed number of sites.
- Percentage of sites which fail at a given laser fluence determined. Plot of % sites which fail as a function of fluence generated
- Linear regression performed on data
- The abscissa of the linear regression fit defines damage threshold



Current ISO Approach





Ideal Case

Typical Case



- Regression fit correlation often poor for defect driven optical components
- Fit is highly dependent on correlation between defect distribution and beam spot size.
- A 1 mm (1/e²) diameter beam is only 180 microns at the 90% point of the beam. (Most "work" done in a small aperture)
- One way to counteract is to measure many sites near the damage threshold. Increases confidence in the data. *Maximum Likelihood Estimation (MLE)* method developed by Neyer.

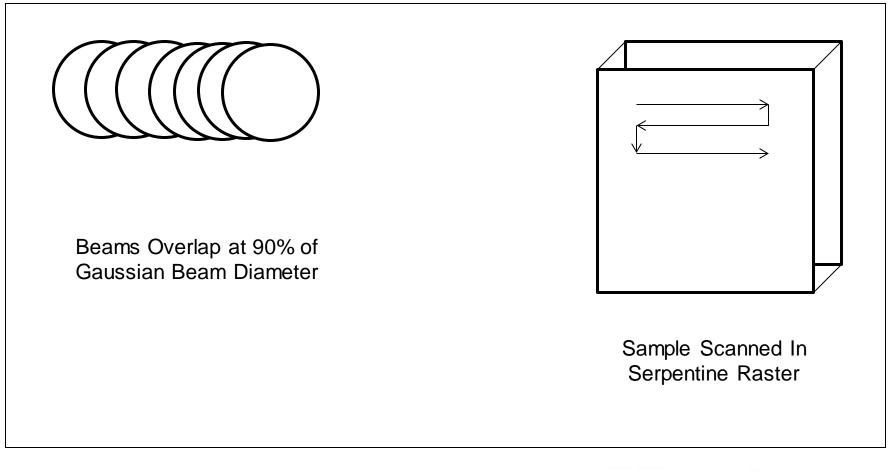


Current TF7 Approach

- Based on A test procedure developed for National Ignition Facility at LLNL.
- Designed to scale small test area to large optical components
- Test defined area at fixed fluence, by raster scanning laser beam
- Increase fluence by fixed amount and rescan same area
- Observe the number of damage occurrences at each fluence level



Current Scanning TF7 Approach





- Scanning allows significant area to be interrogated
- Number of damage sites as *f* (Fluence) can be used to infer defect density and distribution in film
- Damage characteristics and subsequent inspection can differentiate between defect driven and intrinsic damage



TF7 Identifies Two Kinds of Users- Different Needs

- Type 1: Commercial User
 - Can I use this part?
 - Make clear useable aperture
 - · How certain is my knowledge in "safe use"
 - Do "good" parts survive?
 - Are the results repeatable (inter-lab comparison)
 - Not dependent on procedure, laser spot, etc
 - How much damage can be tolerated before laser or optic fails.
 - Is my answer dependent on the "model" used?
 - Can I avoid models altogether?
- Type 2: Research User
 - Have the damage characteristics changed?
 - How have they changed?
 - · How subtle a change can be detected



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TF 7 Is addressing the Type 1 user first.

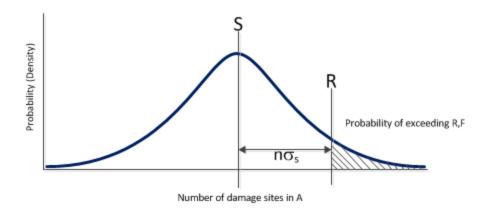
Addressing the Type 1 User

- General, easy to implement test process that applies over many use cases
 - Provides inexpensive quick measurements as well as high confidence more expensive tests
 - Allows end use to define confidence level and tailor that level to the required application
 - Provides functional damage test that can be understood by most users.



Test Procedure Background and Overview

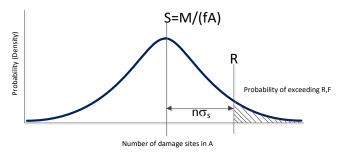
- Most Type 1 users want to know if a given part will survive in a system
 - Can be thought of as allowing
 - A number of sites damaged
 - A total area damaged
- User specifies the maximum number of allowable damages. S, on the optic of area A and the probability (tolerable risk), R, that the true value is larger than S



• This test can be specified in terms of either the number of sites that damage or in terms of area lost (sites*area/site)

Laser Damage Procedure

- Step 1 Calculate the probability of not exceeding R damages in A, P
 P = 1 F
 (1)
- Step 2 Using Figure 1 determine, n the number of standard deviations of offset needed.

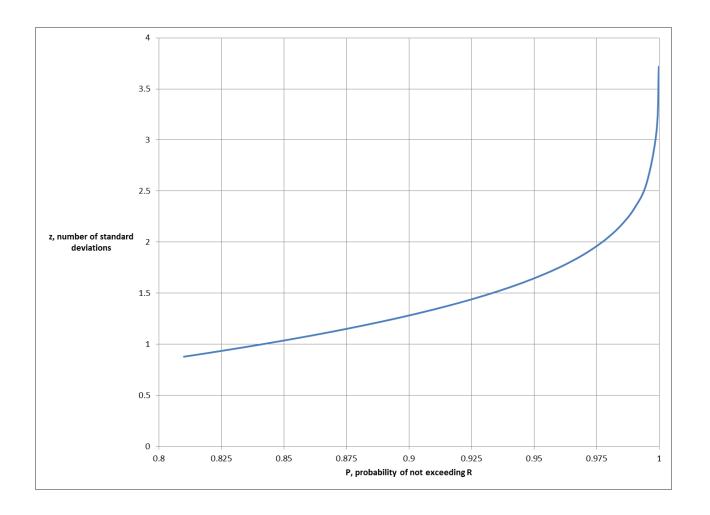


 Step 3 – Determine the upper limit of the number of observed damages, M that can be observed in fA (the area tested, f is the fraction of A exposed), to be at least P likely to have R damages or less in A.

(2)

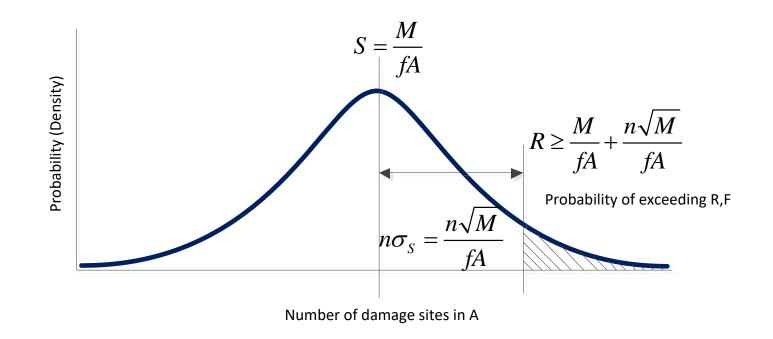
Laser Damage Procedure Concept

Figure 1



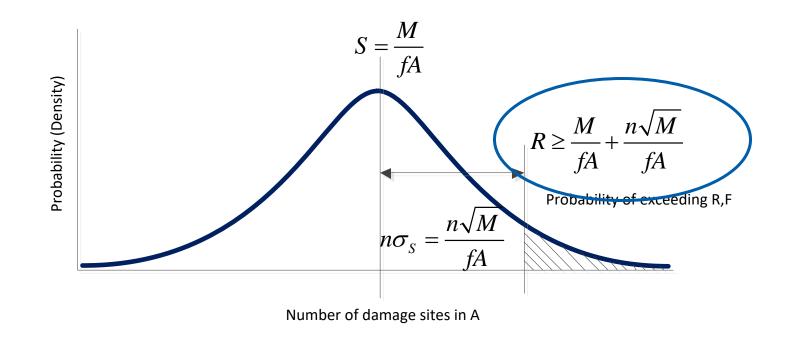
NB: This is possible since the Poisson curve can be well approximated by the Gaussian curve, making this calculation trivial in Excel, Matlab, Mathcad etc.

Explaining (2)



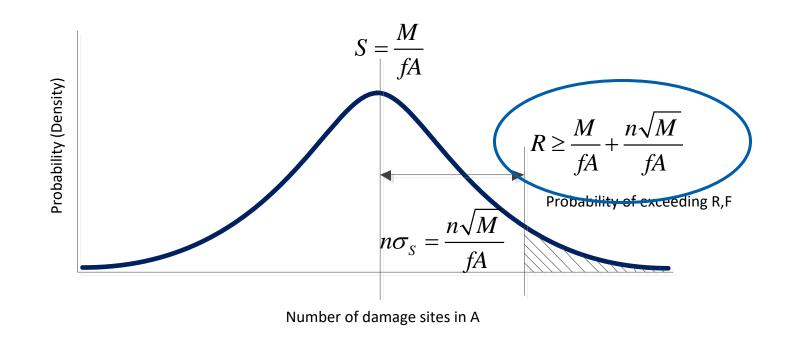
• M and therefore S are described by Poisson statistics

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- In Poisson statistics, the mean and variance have the same value

Explaining (2)



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- In Poisson statistics, the mean and variance have the same value
- The solution to n, is found by solving the quadratic in VM which is (2)

- The user wants to have less than 0.025 chance of having more than R damages on A. So F=0.025
 - P = 1 0.025 = 0.975 from (1)
- From Figure 2, we see that n~2. Equation (2) can then be evaluated for various values of R.
- The results are shown in Figure 3 for R = 10, 20, 50 and 100

Figure 2

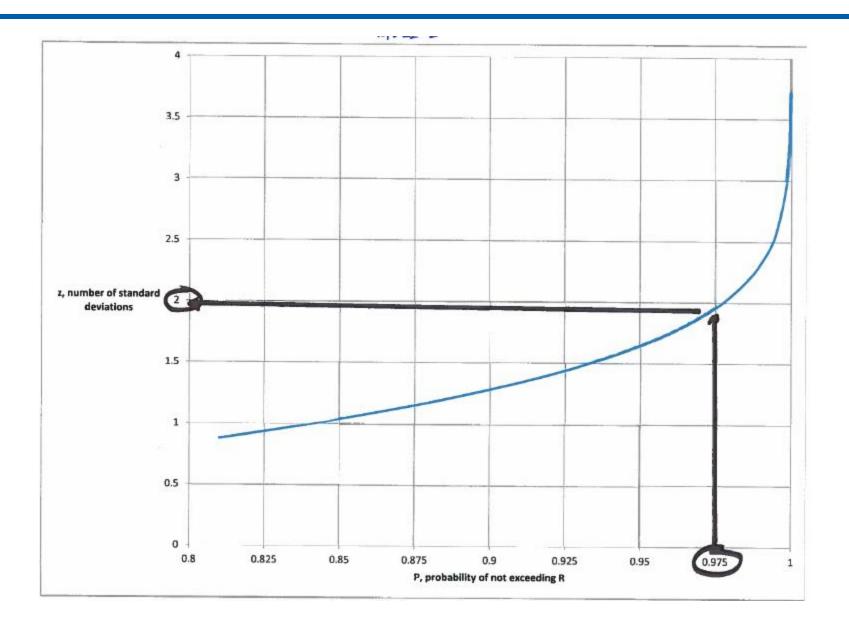
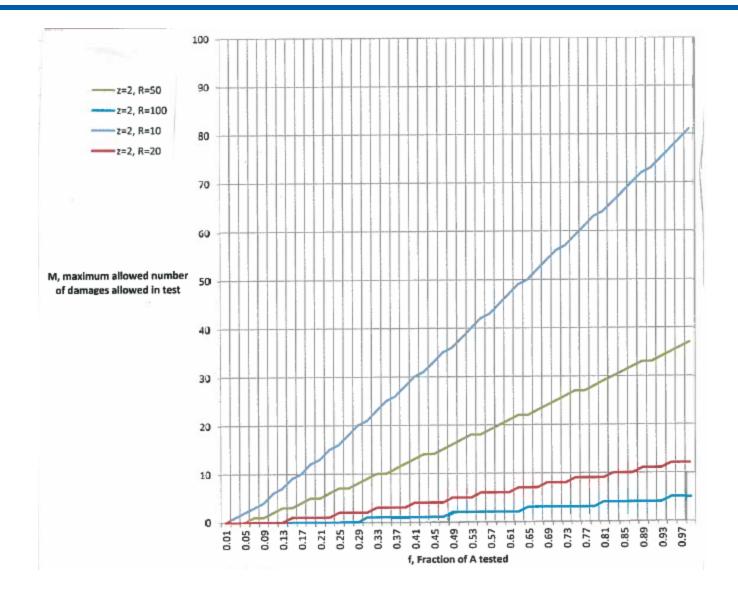
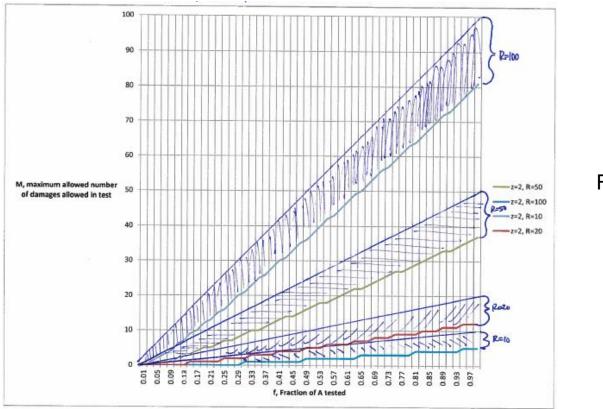


Figure 3



Laser Damage Procedure (Cont.)

 Figure 4 shows the hand drown lines of fR for each R with computer plotted values of M. This distance is essentially the "price of confidence"

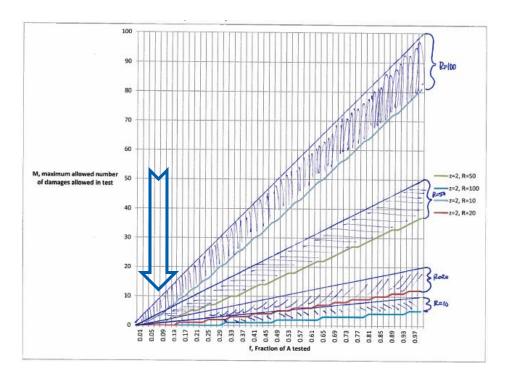




Use Cases

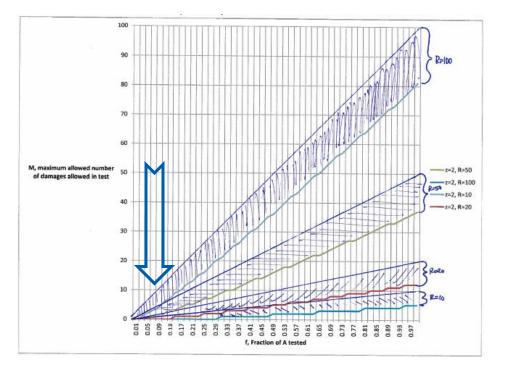
Use Case Analysis: Historical data exists (defect distribution is known)

- In a known and well controlled situation knowledge of f can be used to develop a good small area check
 - Part under test is exposed to higher fluence (and therefore higher cumulative defect density) making



Use Case Analysis: Historical data does not exist

- Testing without any knowledge of f requires large areas to be confident in low defect count
- Low area test cannot differentiate between different values of S
- Only way to be sure is test lots of area (expensive testing)



- ISO 21254 damage threshold measurement remains satisfactory but can be ambigouos.
- LLNL scanning procedure provides more behaved measurement with results not dependent of test procedure.
- OEOSC has defined a test procedure that is "simple" to use and easy to interpret. Hopefully converging on proper statistical methodology.
- This same procedure can be used to estimate a *traditional* on damage threshold (no damage observed) or a *functional* damage threshold (area lost)
- We are seeking input from a wide variety of users, if you have comments or want to submit to the task force, please contact the author.

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